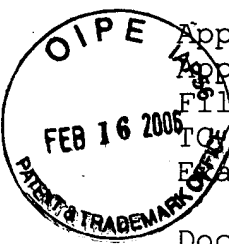


IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

*Ifu*



Appl. No. : 10/727,566  
 Applicant : STÄHLER et al.  
 Filed : December 5, 2003  
 Int. A.U. : 1645  
 Examiner : To Be Assigned

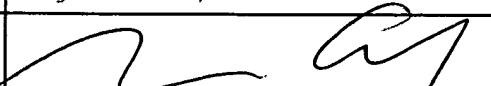
Docket No. : 2923-593  
 Customer No. : 06449  
 Confirmation No. : 7975

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

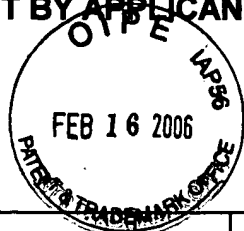
Director of the United States Patent  
 and Trademark Office  
 P.O. Box 1450  
 Alexandria, Virginia 22313-1450

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant submits herewith information that the Office may wish to consider in examination of the subject application. Applicants do not admit that the references submitted herein are prior art to the application. Materials submitted for consideration are listed on the attached Form PTO-1449. German language documents are cited because they were cited in related cases or similar cases having the same assignee in the United States or in Germany. English-language equivalents or abstracts are also submitted where available. Because no substantive action on the merits has been issued in this application, Applicants believe that no fee is due for this submission. If the Office deems that a fee is due, however, Applicants authorize the Director to charge deposit account no. 02-2135.

<b>RESPECTFULLY SUBMITTED,</b>					
NAME AND REG. NUMBER		Martha Cassidy Reg. No. 44,066			
SIGNATURE				DATE	February 16, 2006
Address		Rothwell, Figg, Ernst & Manbeck 1425 K Street, N.W., Suite 800			
City	Washington	State	D.C.	Zip Code	20005
Country	U.S.A.	Telephone	202-783-6040	Fax	202-783-6031

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**



*Complete if Known*

Application Number	10/727,566
Filing Date	December 5, 2003
First Named Inventor	STÄHLER et al.
Group Art Unit	1645
Examiner Name	To Be Assigned
Confirmation No.	7975

Sheet

1

of

7

Attorney Docket Number 2923-593

**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code <sup>2</sup> (if known)		
		5,143,854		PIRRUNG et al.	09-01-1992
		5,247,180		MITCHAM et al.	09-21-1993
		5,318,679		NISHIOKA	06-07-1994
		5,384,464		De FORNEL et al.	01-24-1995
		5,405,783		PIRRUNG et al.	04-11-1995
		5,424,186		FODOR et al.	06-13-1995
		5,474,796		BRENNAN	12-12-1995
		5,547,839		DOWER et al.	08-20-1996
		5,653,939		HOLLIS et al.	08-05-1997
		5,728,251		CHECK, III	03-17-1998
		5,741,411		YEUNG et al.	04-21-1998
		5,789,162		DOWER et al.	08-04-1998
		5,807,525		ALLEN et al.	09-15-1998
		5,812,272		KING et al.	09-22-1998
		5,843,655		McGALL	12-01-1998
		5,846,708		HOLLIS et al.	12-08-1998
		5,849,486		HELLER et al.	12-15-1998
		5,952,172		MEADE et al.	09-14-1999
		5,968,745		THORP et al.	10-19-1999

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		Number	Kind Code <sup>2</sup> (if known)		
		6,001,311		BRENNAN	12-14-1999
		6,024,925		LITTLE et al.	02-15-2000
		6,066,448		WOHLSTADTER et al.	05-23-2000
		6,136,269		WINKLER et al.	10-24-2000
		6,271,957	B1	QUATE et al.	08-07-2001
		6,295,153	B1	GARNER	09-25-2001
		6,375,903	B1	CERRINA et al.	04-23-2002
		6,420,169	B1	READ et al.	07-16-2002
		6,582,917	B1	BEIER	06-24-2003
		6,586,211	B2	STÄHLER et al.	07-01-2003
		2002/0160427	A1	BEIER et al.	10-31-2002
		2003/0175781	A1	BEIER	09-18-2003
		2003/0198948	A1	STÄHLER et al.	10-23-2003
		2004/0043509	A1	STÄHLER et al.	03-04-2004
		2004/0175734	A1	STÄHLER et al.	09-09-2004
		2005/0037407	A1	BEIER et al.	02-17-2005
		60/087,333		QUATE et al.	05-29-1998

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		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
		WO	91/18276	A1	Kelly et al.	11-28-1991	
		WO	93/20230	A1	Environmental & Medical Prod. Ltd.	10-14-1993	
		WO	93/22678	A2	Massachusetts Institute of Tech.	11-11-1993	
		WO	95/09176	A1	Beckman Instruments, Inc.	04-06-1995	
		WO	95/12808	A1	Nanogen, Inc.	05-11-1995	
		WO	96/33971	A1	U.S. Gov't/Secretary of the Navy	10-31-1996	
		WO	96/40712	A1	California Institute of Technology	12-19-1996	
		WO	97/06468	A2	Rabani, Ely	02-20-1997	
		WO	97/12030	A1	Nanogen, Inc.	04-03-1997	
		WO	97/39151	A1	Affymetrix, Inc.	10-23-1997	
		WO	97/41425	A1	Pence, Inc.	11-06-1997	
		WO	98/03683	A1	The Regents of the Univ. of Michigan	01-29-1998	
		WO	98/08085	A1	Science Applications Intl. Corp.	02-26-1998	
		WO	98/30893	A1	Foster, Robert A.	07-16-1998	
		WO	98/51819	A1	Nanogen, Inc.	11-19-1998	
		WO	98/53093	A1	Bioarray Solutions LLC	11-26-1998	
		WO	98/58293 (Abstract)	A2	Biotoole - Institute Fur Computerinte- Griertes Bioengineering GmbH	12-23-1998	AB
		WO	99/09042		Cepheid	02-25-1999	
		WO	99/19510	A1	President and Fellows of Harvard College	04-22-1999	
Examiner Signature					Date Considered		

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		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
		WO	99/27140	A1	Lockheed Martin Energy Res. Corp.	06-03-1999	
		WO	99/31275	A1	Nexstar Pharmaceuticals, Inc.	06-24-1999	
		WO	99/37819	A2	Clinical Micro Sensors, Inc.	07-29-1999	
		WO	99/39817	A1	Affymetrix, Inc.	08-12-1999	
		WO	99/41007	A2	University of Houston	08-19-1999	
		WO	99/42813	A1	Wisconsin Alumni Research Foundation	08-26-1999	
		WO	99/60156	A2	Epigenomics GmbH	11-25-1999	AB
		WO	99/60170	A1	Hyseq, Inc.	11-25-1999	
		WO	99/63385	A1	Board of Regents, Univ. of Texas	12-09-1999	
		WO	00/11473	A1	Sen-Sor-Tech Limited	03-02-2000	
		WO	00/13017	A2	Febit Ferrarius Biotechnology GmbH	03-09-2000	AB
		WO	00/13018	A3	Febit Ferrarius Biotechnology GmbH	03-09-2000	AB
		WO	02/32567 (Abstract)	A1	Febit AG	04-25-2002	AB
		CA	2,345,157		Friz Biochem GmbH	11-19-1999	
		CA	2,371,938	A1	Friz Biochem GmbH	07-20-2000	
		DE	04241871	A1	Schulz, Rudolf	06-16-1994	AB
		DE	04325724	A1	Debbage, Paul	02-02-1995	AB
		DE	19731479	A1	Hewlett-Packard Co.	08-06-1998	AB
Examiner Signature					Date Considered		

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		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
		DE	19823876	A1	Institut fur Mikrotechnik Mainz GmbH	12-02-1999	AB
		DE	19842164	A1	Deutsches Krebsforschungszentrum Stiftung des öffentlichen Rechts	04-06-2000	AB
		DE	19901761	A1	Hartwich, Gerhard	07-01-1999	AB
		DE	19910392	A1	Inst Physikalische Hochtech Ev	09-07-2000	AB
		DE	19921940	A1	Hartwich, Gerhard	06-15-2000	AB
		DE	19926457	A1	Hartwich, Gerhard	07-27-2000	AB
		DE	19940751	A1	FeBIT Ferrarius Biotech.GmbH	03-02-2000	
		DE	69012119	T2	Affymax Technologies N.V.	12-22-1994	
		DE	69032277	T2	SIM (Societe D'In.....	12-17-1998	
		DE	69130251	T2	Matsushita Electrical Indus. Co., Ltd.	05-27-1999	
		DE	69217497	T2	Affymax Technologies N.V.	06-12-1997	
		DE	69218572	T2	Texas Instruments Inc.	11-13-1997	
		DE	69328693	T2	Beckman Coulter, Inc.	08-31-2000	
		DE	8309254.4		Straub, Hans	01-03-1985	
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		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
		EP	0430248	A2	Mochida Pharmaceutical Co., Ltd.	06-05-1991	
		EP	0493137	A1	Research Development Corporation of Japan	07-01-1992	
		EP	0549993	A1	Texas Instruments Inc.	07-07-1993	
		EP	0671626	A1	Ciba-Geigy AG	09-13-1995	
		EP	0955085	A2	Affymetrix, Inc.	11-10-1999	
		JP	9288080 (Abstract)		Shinnitsuka Kankyo Eng KK	11-04-1997	AB
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NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>	
		Anonymous, Digital Optical Chemistry System, 12/20/99, from Internet.		
		Bertsch et al., "Study of the Spatial Resolution of a New 3D Microfabrication Process: The Microstereophotolithography Using a Dynamic Mask-generator Technique," J. Photochemistry Photobiology A: Chemistry 107:275-281, 1997.		
		Bertsch et al., "Study of the Spatial Resolution of a New 3D Microfabrication Process: The Microstereophotolithography Using a Dynamic Mask-generator Technique," Chem. Abstr., 127(15):212440, 1997 (Abstract).		
		Davidson, "A Microlens Direct-Write Concept for Lithography," SPIE 3048:346-355.		
		Hanley, et al. "Charge Transfer Device in Analytical Instrumentation," Anal. Chem. 68:A661-A667, 1996.		
		Johnson et al., "Micromirror arrays perform photolithography step," EETIMES.com, (1999), 2 pgs.		
		Kirschner, et al., "Miniaturisierte NIR-Diodenarray-Spektrometer," GIT Labor-Fachzeitschrift (English Title Translation: Miniaturized NIR Diode Array Spectrometers), 402-404, 1998.		
		Neff, et al., "Two-Dimensional Spatial Light Modulators: A Tutorial," Proc. IEEE, 78(5):826-854, 1990.		
		Singh-Gasson et al., "Maskless Fabrication of Light-directed Oligonucleotide Microarrays Using a Digital Micromirror Array," Nat. Biotechnol., 17:974-978, 1999.		
		Villemoes et al., "A Computerized Peptide Synthesizer with Feed back Control," Acta Chemica Scand. B 32:703-713, 1978.		
		von Buren et al., "Branched Oligodeoxynucleotides: Automated Synthesis and Triple Helical Hybridization Studies," Tetrahedron Lett. 51(31):8491-8506, 1995.		
		German Search Report of 08/9/1999, from DE 19839254.0 (with English translation).		✓
		German Search Report of 04/17/2000, from DE 19940752.5 (with English translation).		✓
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